77		USPAT;	1 =	l
	or die or circuit or image) with	US-PGPUB	17:06	
	(difference or subtract\$4) with (select\$4	1		
1	or choos\$4 or determin\$4)) and inspect\$4			- 1
5.	die adj die adj inspection	USPAT;	2002/04/12	
		US-PGPUB	17:06	
107	die adj2 die with inspection	USPAT;	2002/04/12	
		US-PGPUB	17:07	
1	(die adi2 die with inspection) and	USPAT;	2002/04/12	١.
]		US-PGPUB	17:08	
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}		ł		
16		USPAT;	2002/04/12	
	(reference or template or model) near	US-PGPUB	17:09	
	(choos\$4 or determin\$4 or select\$4)	1		
	107 1	or die or circuit or image) with (difference or subtract\$4) with (select\$4 or choos\$4 or determin\$4)) and inspect\$4 die adj die adj inspection 107 die adj2 die with inspection 1 (die adj2 die with inspection) and (reference or template or model) near (choos\$4 or determin\$4 or select\$4) with (difference or subtract\$4) with image (die adj2 die with inspection) and (reference or template or model) near	or die or circuit or image) with (difference or subtract\$4) with (select\$4 or choos\$4 or determin\$4)) and inspect\$4 die adj die adj inspection 107 die adj2 die with inspection 1 (die adj2 die with inspection) and (reference or template or model) near (choos\$4 or determin\$4 or select\$4) with (difference or subtract\$4) with image (die adj2 die with inspection) and (reference or template or model) near (reference or template or model) near (reference or template or model) near	or die or circuit or image) with (difference or subtract\$4) with (select\$4 or choos\$4 or determin\$4)) and inspect\$4 die adj die adj inspection 107 die adj2 die with inspection 1 (die adj2 die with inspection) and (reference or template or model) near (choos\$4 or determin\$4 or select\$4) with (difference or subtract\$4) with image 16 (die adj2 die with inspection) and (reference or template or model) near

Number 11 1	*****				
Number 609	L	Hits	Search Text	DB	Time stamp
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